# GP1S97J0000F

Gap : 2.2mm, Slit : 0.3mm Phototransistor Output, **Compact Transmissive Photointerrupter** 



#### Description

GP1S97J0000F is a compact-package, phototransistor output, transmissive photointerrupter, with opposing emitter and detector in a molding that provides noncontact sensing. The compact package series is a result of unique technology combing transfer and injection molding.

This device has hole that passes through the base of the device, for assembly or fixing, and it has a wide gap.

#### Features

- 1. Transmissive with phototransistor output
- 2. Highlights :
  - Compact Size
  - Wide Gap
- 3. Key Parameters :
  - Gap Width : 2.2mm
  - Slit Width (detector side): 0.3mm
  - Package : 5×3.4×5.2mm
- 4. Lead free and RoHS directive compliant

#### Agency approvals/Compliance

1. Compliant with RoHS directive

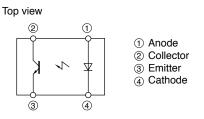
#### Applications

- 1. Detection of object presence or motion.
- 2. Example : printer, lens control for camera

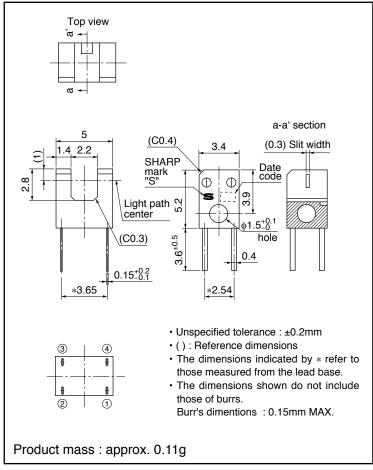
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#### ■ Internal Connection Diagram



#### ■ Outline Dimensions



Plating material : SnCu (Cu : TYP. 2%)

(Unit : mm)

## SHARP

### Date code (2 digit)

	· 3	/	
1st digit		2nd digit	
Year of production		Month of production	
A.D.	Mark	Month	Mark
2000	0	1	1
2001	1	2	2
2002	2	3	3
2003	3	4	4
2004	4	5	5
2005	5	6	6
2006	6	7	7
2007	7	8	8
2008	8	9	9
2009	9	10	X
2010	0	11	Y
:	:	12	Z

repeats in a 10 year cycle

#### Rank mark

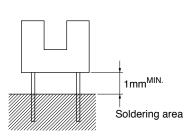
There is no rank indicator.

Country of origin Japan



## Absolute Maximum Ratings

■ Absolute Maximum Ratings (T <sub>a</sub> =25°C)				
	Parameter	Symbol	Rating	Unit
	Forward current	I <sub>F</sub>	50	mA
Input	Reverse voltage	V <sub>R</sub>	6	V
	Power dissipation	Р	75	mW
Output	Collector-emitter voltage	V <sub>CEO</sub>	35	V
	Emitter-collector voltage	V <sub>ECO</sub>	6	V
	Collector current	I <sub>C</sub>	20	mA
	Collector power dissipation	P <sub>C</sub>	75	mW
Total power dissipation		P <sub>tot</sub>	100	mW
Operating temperature		T <sub>opr</sub>	-25 to +85	°C
Storage temperature		T <sub>stg</sub>	-40 to +100	°C
*1Soldering temperature		T <sub>sol</sub>	260	°C



\*1 For 5s or less

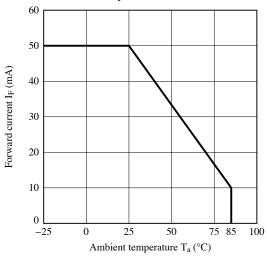
#### ■ Electro-optical Characteristics

 $(T_a=25^{\circ}C)$ 

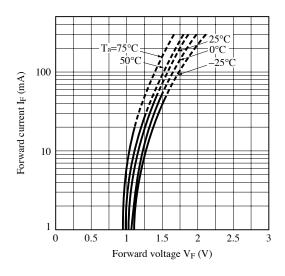
-							
Parameter		Symbol	Condition	MIN.	TYP.	MAX.	Unit
Forward voltage		$V_{\rm F}$	I <sub>F</sub> =20mA	_	1.2	1.4	V
Reverse current		I <sub>R</sub>	V <sub>R</sub> =3V	-	-	10	μA
ut Collector dark current		I <sub>CEO</sub>	$V_{CE}=20V$	-	-	100	nA
nsfer Collector current		I <sub>C</sub>	$V_{CE}=5V, I_{F}=5mA$	80	-	400	μΑ
Collector-emitter saturation voltage		V <sub>CE(sat)</sub>	$I_F=10mA$ , $I_C=40\mu A$	_	-	0.4	V
Paspansa tima	Rise time	t <sub>r</sub>	V 5V I 100 A P 11-0	_	50	150	μs
teristics Response time	Fall time	t <sub>f</sub>	$v_{CE}=3v$ , $i_{C}=100\mu A$ , $K_{L}=1KS2$	-	50	150	μs
	orward voltage everse current ollector dark current ollector current	orward voltage everse current ollector dark current ollector current ollector-emitter saturation voltage esponse time	orward voltage $V_F$ everse current $I_R$ ollector dark current $I_{CEO}$ ollector current $I_C$ ollector-emitter saturation voltage $V_{CE(sat)}$ esponse time     Rise time $t_r$	orward voltage $V_F$ $I_F=20mA$ everse current $I_R$ $V_R=3V$ ollector dark current $I_{CEO}$ $V_{CE}=20V$ ollector current $I_C$ $V_{CE}=5V, I_F=5mA$ ollector-emitter saturation voltage $V_{CE(sat)}$ $I_F=10mA, I_C=40\mu A$ esponse time     Rise time $t_r$ $V_{CE}=5V, I_C=100\mu A, R_L=1kQ$	orward voltage $V_F$ $I_F=20mA$ -         everse current $I_R$ $V_R=3V$ -         ollector dark current $I_{CEO}$ $V_{CE}=20V$ -         ollector current $I_C$ $V_{CE}=5V, I_F=5mA$ 80         ollector-emitter saturation voltage $V_{CE(sat)}$ $I_F=10mA, I_C=40\mu A$ -         esponse time       Rise time $t_r$ $V_{CE}=5V, I_C=100\mu A, R_L=1kQ$ -	orward voltage $V_F$ $I_F=20mA$ -1.2everse current $I_R$ $V_R=3V$ ollector dark current $I_{CEO}$ $V_{CE}=20V$ ollector current $I_C$ $V_{CE}=5V, I_F=5mA$ 80-ollector-emitter saturation voltage $V_{CE(sat)}$ $I_F=10mA, I_C=40\mu A$ Rise time $t_r$ $V_{CE}=5V, I_C=100\mu A, R_L=1kQ$ -50	orward voltage $V_F$ $I_F=20mA$ -1.21.4everse current $I_R$ $V_R=3V$ 10ollector dark current $I_{CEO}$ $V_{CE}=20V$ 100ollector current $I_C$ $V_{CE}=5V, I_F=5mA$ 80-400ollector-emitter saturation voltage $V_{CE(sat)}$ $I_F=10mA, I_C=40\mu A$ 0.4Normality of the time trVoltage time tr

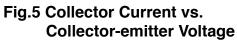






#### Fig.3 Forward Current vs. Forward Voltage





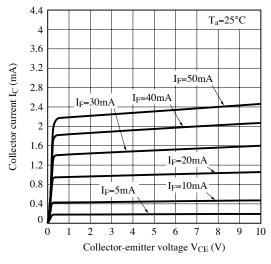
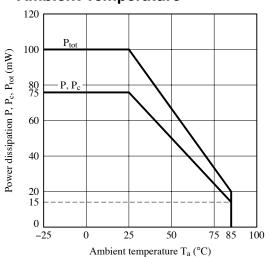
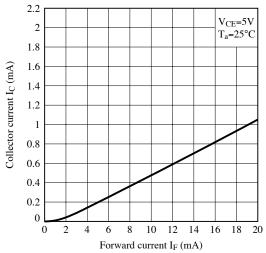


Fig.2 Power Dissipation vs. Ambient Temperature









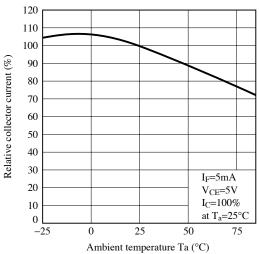
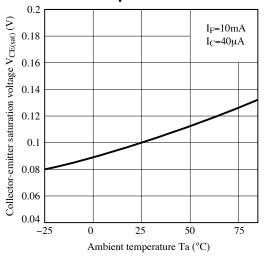
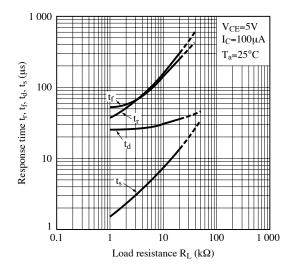




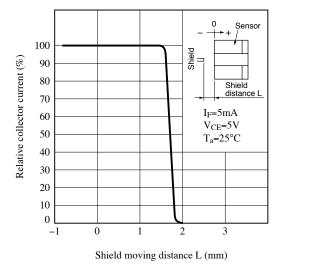
Fig.7 Collector-emitter Saturation Voltage vs. Ambient Temperature



#### Fig.9 Response Time vs. Load Resistance

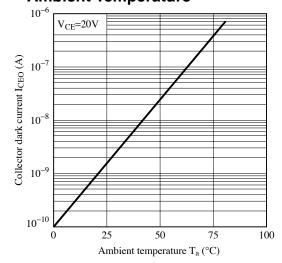


#### Fig.11 Detecting Position Characteristics (1)

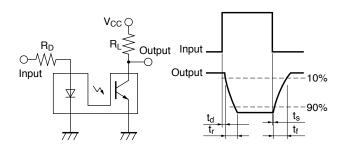


Remarks : Please be aware that all data in the graph are just for reference and not for guarantee.

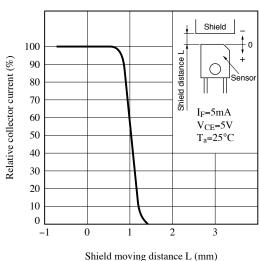
Fig.8 Collector Dark Current vs. Ambient Temperature



#### Fig.10 Test Circuit for Response Time









#### Design Considerations

#### • Design guide

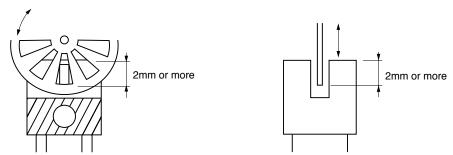
1) Prevention of detection error

To prevent photointerrupter from faulty operation caused by external light, do not set the detecting face to the external light.

2) Position of opaque board

Opaque board shall be installed at place 2mm or more from the top of elements.





This product is not designed against irradiation and incorporates non-coherent IRED.

#### Degradation

In general, the emission of the IRED used in photointerrupter will degrade over time.

In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

#### Parts

This product is assembled using the below parts.

#### • Photodetector (qty. : 1)

Category	Material	Maximum Sensitivity wavelength (nm)	Sensitivity wavelength (nm)	Response time (µs)
Phototransistor	Silicon (Si)	930	700 to 1 200	20

#### • Photo emitter (qty. : 1)

Category	Material	Maximum light emitting wavelength (nm)	I/O Frequency (MHz)
Infrared emitting diode (non-coherent)	Gallium arsenide (GaAs)	950	0.3

#### Material

Case	Lead frame	Lead frame plating
Black polyphernylene sulfide resin (UL94 V-0)	42Alloy	SnCu plating



#### Manufacturing Guidelines

#### Soldering Method

Flow Soldering:

Soldering should be completed below 260°C and within 5 s.

Please solder within one time.

Soldering area is 1mm or more away from the bottom of housing.

Please take care not to let any external force exert on lead pins.

Please don't do soldering with preheating, and please don't do soldering by reflow.

#### Hand soldering

Hand soldering should be completed within 3 s when the point of solder iron is below 350°C. Please solder within one time.

Please don't touch the terminals directly by soldering iron.

Soldered product shall treat at normal temperature.

#### Other notice

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the cooling and soldering conditions.

#### Cleaning instructions

#### Solvent cleaning :

Solvent temperature should be 45°C or below. Immersion time should be 3 minutes or less.

Ultrasonic cleaning :

Do not execute ultrasonic cleaning.

#### Recommended solvent materials :

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol.

#### Presence of ODC

This product shall not contain the following materials. And they are not used in the production process for this product. Regulation substances : CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBBOs and PBBs are not used in this product at all.

This product shall not contain the following materials banned in the RoHS Directive (2002/95/EC).
Lead, Mercury, Cadmium, Hexavalent chromium, Polybrominated biphenyls (PBB), Polybrominated diphenyl ethers (PBDE).



#### ■ Package specification

#### Sleeve package

Package materials Sleeve : Polystyrene Stopper : Styrene-Elastomer

Package method

MAX. 50 pcs. of products shall be packaged in a sleeve. Both ends shall be closed by tabbed and tabless stoppers.

MAX. 50 sleeves in one case.

# SHARP

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- --- Office automation equipment
- --- Telecommunication equipment [terminal]
- --- Test and measurement equipment
- --- Industrial control
- --- Audio visual equipment
- --- Consumer electronics

(ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection with equipment that requires higher reliability such as:

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- --- Traffic signals
- --- Gas leakage sensor breakers
- --- Alarm equipment
- --- Various safety devices, etc.

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- --- Telecommunication equipment [trunk lines]
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